

Notice of References Cited	Application/Control No. 10/580,605	Applicant(s)/Patent Under Reexamination ITO, HISAYOSHI	
	Examiner Liam J. Heincer	Art Unit 1709	Page 1 of 4

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Notice of References Cited	Application/Control No. 10/580,605		Applicant(s)/Patent Under Reexamination ITO, HISAYOSHI	
	Examiner Liam J. Heincer		Art Unit 1709	Page 2 of 4

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Notice of References Cited	Application/Control No. 10/580,605	Applicant(s)/Patent Under Reexamination ITO, HISAYOSHI	
	Examiner Liam J. Heincer	Art Unit 1709	Page 3 of 4

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ITO, HISAYOSHI

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Art Unit

1709

Page 4 of 4

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